

ABSTRACT

[0033] A low capacitance measurement probe is disclosed. The low capacitance measurement probe comprises an outer conductor forming an outer wall having an exterior and an interior; a non-conductive spacer forming a first wall having an exterior and an interior with the non-conductive spacer being coupled to the interior of the outer conductor; a conductive layer forming a second wall having an exterior and an interior, the conductive layer coupled to the interior of the first wall; an insulating layer forming a third wall having an exterior and an interior, the insulating layer coupled to the interior of the second wall; and an inner conductor forming an inner wall having an exterior and an interior, the inner conductor coupled to the interior of the third wall. A low capacitance measurement probe system and a method of using a low capacitance measurement probe are also disclosed.